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Application No. <u>09/890 656</u>	Prepared by <u>NMB</u>	Tracking Number <u>05980/08</u>	
Examiner-GAU <u>TPM-2811</u>	Date <u>8/9/04</u>	Week Date <u>7/12/04</u>	
	No. of queries <u>1</u>	<u>IPW(E)</u>	

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE
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d. Other Missing Text	
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g. Brief Description	
h. Sequence Listing	
i. Appendix	
j. Amendments	
k. Other	<u>Thank You</u>
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CLAIMS	RESPONSE
a. Claim(s) Missing	
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FORM PTO-1449
(REV. 7-80)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. : 579903a

SERIAL NO. 09/890,656

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT : Reinhard Schauer et al.

FILING DATE August 2, 2001

GROUP: 2811

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AR		SZE, S.H.: Physics of Semiconductor Devices, New York, Wiley, 1969, p. 43
	AS		Ohshita, Y. et al; Journal of Crystal Growth, 1991, vol. 108, pp. 499-507
	AT		Hammond, M.L.; Silicon Epitaxy, Solid State Technology, 1978, H. 11, pp. 68-75

EXAMINER *Thien VNM*

DATE CONSIDERED 01-08-03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.